

<b>Notice of References Cited</b>	Application/Control No. 09/801,200		Applicant(s)/Patent Under Reexamination SHIMAZAKI ET AL.	
	Examiner Shambhavi Patel		Art Unit 2128	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,035,048	03-2000	Diethorn, Eric John	381/94.3
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	Hayashi et al. 'EMI-Noise Analysis under ASIC Design Environment'. ACM Press, 1999; pages 16-21
	V	Cheng et al. 'Power Supply Noise Analysis Methodology for Deep-Submicron VLSI Chip Design.' ACM 1997.
	W	'Engineer to Engineer Note' Analog Devices 1996.
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.